Se	arch	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/743,147	CHEN, CHIH-YUAN	
Examiner	Art Unit	
Joseph Haley	2627	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
see updated EAST search notes	9/26/2007	JRH	
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